



# CERTIFICATE OF ACCREDITATION

**ANSI National Accreditation Board**  
11617 Coldwater Road, Fort Wayne, IN 46845 USA

This is to certify that

**System Scale Corporation**  
**8101 Industry Drive**  
**North Little Rock, AR 72117**

has been assessed by ANAB and meets the requirements of international standard

**ISO/IEC 17025:2017**

and national standards

**ANSI/NCSL Z540-1-1994 (R2002)**

while demonstrating technical competence in the field of

**CALIBRATION**

Refer to the accompanying Scope of Accreditation for information regarding the types of activities to which this accreditation applies

AC-1756  
Certificate Number

  
ANAB Approval

Certificate Valid Through: 02/01/2021  
Version No. 010 Issued: 02/05/2020



This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).



SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017 AND ANSI/NCSL Z540-1-1994 (R2002)

System Scale Corporation

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CALIBRATION

Valid to: February 1, 2021

Certificate Number: AC-1756

Acoustics and Vibration

Table with 4 columns: Parameter/Equipment, Range, Expanded Uncertainty of Measurement (+/-), Reference Standard, Method, and/or Equipment. Row 1: Sound level meter, 94 dB to 114 dB, 0.55 dB, Sound standard.

Chemical Quantities

Table with 4 columns: Parameter / Equipment, Range, Expanded Uncertainty of Measurement (+/-), Reference Standard, Method and/or Equipment. Rows include pH Meters and Conductivity with their respective ranges and uncertainties.

Electrical – DC/Low Frequency

Table with 4 columns: Parameter / Equipment, Range, Expanded Uncertainty of Measurement (+/-), Reference Standard, Method and/or Equipment. Row 1: DC Voltage – Measure with ranges from 10 mV to 1 kV and corresponding uncertainties.



Electrical – DC/Low Frequency

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
DC Voltage - Source <sup>1</sup>	(0 to 329.9) mV (0 to 3.299) V (0 to 32.999) V (30 to 329.999) V 100 V to 1.02 kV	6.6 $\mu$ V/V + 1 $\mu$ V 35 $\mu$ V/V + 2 $\mu$ V 0.4 mV/V + 20 $\mu$ V 5.9 mV/V + 0.15 mV 19 mV/V + 1.5 mV	Fluke 5522A/SC600 Multi Product Calibrator
DC Current - Measure <sup>1</sup>	(10 to 100) $\mu$ A 100 $\mu$ A to 10 mA (10 to 100) mA 100 mA to 1 A	28 $\mu$ A/A + 8 $\mu$ A 25 $\mu$ A/A + 5 $\mu$ A 45 $\mu$ A/A + 5 $\mu$ A 0.18 mA/A + 10 $\mu$ A	HP 3458A Opt 002 Multimeter
DC Current - Source <sup>1</sup>	(0 to 329.9) $\mu$ A (0 to 3.299 9) mA (0 to 32.999) mA (0 to 329.99) mA (0 to 1.099 9) A (1.1 to 2.999) A (0 to 10.99) A (11 to 20.5) A	50 nA/A + 20 nA 0.33 $\mu$ A/A + 50 nA 3.3 $\mu$ A/A + 0.25 $\mu$ A 33 $\mu$ A/A + 2.5 $\mu$ A 0.22 mA/A + 40 $\mu$ A 1.1 mA/A + 40 $\mu$ A 5.5 mA/A + 0.5 mA 21 mA/A + 0.75 mA	Fluke 5522A/SC600 Multi Product Calibrator
AC Voltage – Measure <sup>1</sup>	(10 to 100) mV (1 to 40) Hz 40 Hz to 1 kHz (1 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz 100 mV to 10 V (1 to 40) Hz 40 Hz to 1 kHz (1 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz 300 kHz to 1 MHz (1 to 2) MHz (10 to 100) V (1 to 40) Hz 40 Hz to 1 kHz (1 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz 300 kHz to 1 MHz	0.3 mV/V + 30 $\mu$ V 0.2 mV/V + 11 $\mu$ V 0.3 mV/V + 11 $\mu$ V 1 mV/V + 11 $\mu$ V 5 mV/V + 11 $\mu$ V 40 mV/V + 20 $\mu$ V 0.7 mV/V + 0.4 mV 0.7 mV/V + 0.2 mV 1.4 mV/V + 0.2 mV 3 mV/V + 0.2 mV 8 mV/V + 0.3 mV 30 mV/V + 1 mV 0.1 V/V + 1mV 0.1 V/V + 1 mV 20 mV/V + 4 mV 20 mV/V + 2 mV 20 mV/V + 2 mV 35 mV/V + 2 mV 0.1 V/V + 2 mV 0.4 V/V + 10 mV 1.5 V/V + 10 mV	HP 3458A opt 002 Multimeter



Electrical – DC/Low Frequency

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
AC Voltage – Measure <sup>1</sup>	100 V to 1 kV (1 to 40) Hz 40 Hz to 1 kHz (1 to 20) kHz (20 to 50) kHz (50 to 100) kHz	0.4 V/V + 40 mV 0.4 V/V + 20 mV 0.6 V/V + 20 mV 1 V/V + 20 mV 3 V/V + 20 mV	HP 3458A opt 002 Multimeter
AC Voltage - Source <sup>1</sup>	(1 to 32.99) mV (10 to 40) Hz 45 Hz to 10 kHz (10 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 500) kHz (33 to 329.99) mV (10 to 45) Hz 45 Hz to 10 kHz (10 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 500) kHz (0.33 to 3.299) V (10 to 45) Hz 45 Hz to 10 kHz (20 to 50) kHz (50 to 100) kHz (100 to 500) kHz (3.3 to 32.99) V (10 to 45) Hz 45 Hz to 10 kHz (10 to 20) kHz 20 to 50 kHz 50 to 100 kHz (33 to 329.99) V 45 Hz to 1 kHz (1 to 10) kHz (10 to 20) kHz (20 to 50) kHz (50 to 100) kHz	26 μV/V + 6 μV 5 μV/V + 6 μV 6.6 μV/V + 6 μV 33 μV/V + 6 μV 0.11 mV/V + 12 μV 0.26 mV/V + 50 μV 99 μV/V + 8 μV 48 μV/V + 8 μV 53 μV/V + 8 μV 0.12 mV/V + 8 μV 0.26 mV/V + 32 μV 0.66 mV/V + 70 μV 0.99 mV/V + 50 μV 0.5 mV/V + 60 μV 0.63 mV/V + 60 μV 23 mV/V + 0.13 mV 7.9 mV/V + 0.6 mV 9.9 mV/V + 0.65 mV 5 mV/V + 0.6 mV 7.9 mV/V + 0.6 mV 12 mV/V + 0.6 mV 30 mV/V + 1.6 mV 63 mV/V + 2 mV 66 mV/V + 6 mV 83 mV/V + 6 mV 99 mV/V + 6 mV 660 V/V + 6 mV	Fluke 5522A/SC600 Multi Product Calibrator



# ANSI National Accreditation Board

## Electrical – DC/Low Frequency

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
AC Voltage - Source <sup>1</sup>	(330 to 1 020) V 45 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz	0.31 V/V + 10 mV 0.26 V/V + 10 mV 0.31 V/V + 10 mV	Fluke 5522A/SC600 Multi Product Calibrator
AC Voltage - Source <sup>1</sup> (AUX output)	(10 to 329.99) mV (10 to 20) Hz (20 to 45) Hz 45 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz (10 to 30) kHz (0.33 to 3.299) V (10 to 20) Hz (20 to 45) Hz 45 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz (10 to 30) kHz (3.3 to 5) V (10 to 20) Hz (20 to 45) Hz 45 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz	0.66 mV/V + 0.37 mV 0.66 mV/V + 0.37 mV 0.66 mV/V + 0.37 mV 0.66 mV/V + 0.45 mV 1.32 mV/V + 0.45 mV 16.5 mV/V + 0.9 mV 6.6 mV/V + 0.45 mV 6.6 mV/V + 0.45 mV 3 mV/V + 0.45 mV 6.6 mV/V + 1.4 mV 13 mV/V + 1.4 mV 0.165 V/V + 2.8 mV 0.01 V/V + 0.45 mV 5 mV/V + 450 μV 4.5 mV/V + 450 μV 0.01 V/V + 1.4 mV 0.02 V/V + 1.4 mV	Fluke 5522A/SC600 Multi Product Calibrator
Resistance - Source <sup>1</sup>	(0 to 10.9) Ω (11 to 32.9) Ω (33 to 109.99) Ω (110 to 329.99) Ω (0.33 to 1.09) kΩ (1.1 to 3.299) kΩ (3.3 to 10.99) kΩ (11 to 32.999) kΩ (33 to 109.99) kΩ (110 to 329.9) kΩ (33 to 1.09) MΩ (1.1 to 3.29) MΩ (3.3 to 10.9) MΩ (11 to 32.99) MΩ (33 to 109.99) MΩ (110 to 329.99) MΩ (330 to 1 100) MΩ	0.4 mΩ/Ω + 10 mΩ 1 mΩ/Ω + 15 mΩ 3 mΩ/Ω + 15 mΩ 9.2 mΩ/Ω + 20 mΩ 31 mΩ/Ω + 20 mΩ 92 mΩ/Ω + 0.2 Ω 0.31 Ω/Ω + 0.1 Ω 0.92 Ω/Ω + 1 Ω 3.1 Ω/Ω + 1 Ω 11 Ω/Ω + 10 Ω 35 Ω/Ω + 10 Ω 0.2 kΩ/Ω + 0.15 kΩ 1.4 kΩ/Ω + 0.25 kΩ 8.3 kΩ/Ω + 2.5 kΩ 55 kΩ/Ω + 3 kΩ 0.99 MΩ/Ω + 0.1 MΩ 17 MΩ/Ω + 0.5 MΩ	Fluke 5522A/SC600 Multi Product Calibrator



# ANSI National Accreditation Board

## Electrical – DC/Low Frequency

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
Resistance - Measure <sup>1</sup>	(1 to 10) Ω (10 to 100) Ω 100 Ω to 100 kΩ 100 k Ω to 1 MΩ (1 to 10) MΩ (10 to 100) MΩ 100 M Ω to 1 GΩ	23 μΩ/Ω + 0.1 mΩ 23 μΩ/Ω + 0.1 mΩ 11 μΩ/Ω + 0.1 Ω 63 μΩ/Ω + 4 Ω 0.83 Ω/Ω + 100 Ω 0.1 mΩ/Ω + 10 kΩ 10 mΩ/Ω + 10 kΩ	HP 3458A Opt 002 Multimeter
AC Current - Measure <sup>1</sup>	(10 to 100) μA (10 to 20) Hz (20 to 45) Hz 45 Hz to 1 kHz 100 μA to 100 mA (10 to 20) Hz (20 to 45) Hz 45 Hz to 100 Hz 100 Hz to 5 kHz (5 to 20) kHz (20 to 50) kHz (50 to 100) kHz 100 mA to 1 A (10 to 20) Hz (20 to 45) Hz 45 Hz to 100 Hz 100 Hz to 5 kHz (5 to 20) kHz (20 to 50) kHz	0.4 μA/A + 0.03 μA 0.2 μA/A + 0.03 μA 0.1 μA/A + 0.03 μA 0.4 mA/A + 20 μA 0.2 mA/A + 20 μA 0.1 mA/A + 20 μA 0.1 mA/A + 20 μA 0.1 mA/A + 20 μA 0.1 mA/A + 20 μA 0.4 mA/A + 40 μA 0.6 mA/A + 0.15 mA 4 mA/A + 0.2 mA 2 mA/A + 0.2 mA 1 mA/A + 0.2 mA 1 mA/A + 0.2 mA 3 mA/A + 0.2 mA 10 mA/A + 0.4 mA	HP 3458A Opt 002 Multimeter
AC Current - Source <sup>1</sup>	(29 to 329.99) μA (10 to 20) Hz (20 to 45) Hz 45 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz (10 to 30) kHz (0.33 to 3.299) mA (10 to 20) Hz (20 to 45) Hz 45 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz (10 to 30) kHz	0.66 μA + 0.1 μA 0.5 μA + 0.1 μA 0.41 μA + 0.1 μA 0.99 μA + 0.15 μA 2.6 μA + 0.2 μA 5.3 μA + 0.4 μA 6.6 μA + 0.15 μA 4.1 μA + 0.15 μA 3.3 μA + 0.15 μA 6.6 μA + 0.2 μA 17 μA + 0.3 μA 33 μA + 0.6 μA	Fluke 5522A/SC600 Multi Product Calibrator

**Electrical – DC/Low Frequency**

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
AC Current - Source <sup>1</sup>	(3.3 to 32.99) mA		Fluke 5522A/SC600 Multi Product Calibrator
	(10 to 20) Hz	59 $\mu$ A + 2 $\mu$ A	
	(20 to 45) Hz	30 $\mu$ A + 2 $\mu$ A	
	45 Hz to 1 kHz	13 $\mu$ A + 2 $\mu$ A	
	(1 to 5) kHz	26 $\mu$ A + 2 $\mu$ A	
	(5 to 10) kHz	66 $\mu$ A + 2 $\mu$ A	
	(33 to 329.99) mA		
	(10 to 20) Hz	0.59 mA + 20 $\mu$ A	
	(20 to 45) Hz	0.3 mA + 20 $\mu$ A	
	45 Hz to 1 kHz	0.13 mA + 20 $\mu$ A	
	(1 to 5) kHz	0.33 mA + 50 $\mu$ A	
	(5 to 10) kHz	0.66 mA + 0.1 mA	
	(10 to 30) kHz	1.3 mA + 0.2 mA	
	(0.33 to 1.099 9) A		
	(10 to 45) Hz	2 mA + 0.1 mA	
	45 Hz to 1 kHz	0.55 mA + 0.1mA	
(1 to 5) kHz	6.6 mA + 1 mA		
(5 to 10) kHz	28 mA + 5 mA		
(1.1 to 2.999) A			
(10 to 45) Hz	5.4 mA + 100 $\mu$ A		
45 Hz to 1 kHz	1.8 mA + 100 $\mu$ A		
(1 to 5) kHz	18 mA + 1 mA		
(5 to 10) kHz	75 mA + 5 mA		
(3 to 10.99) A			
(45 to 100) Hz	6.6 mA + 2 mA		
100 Hz to 1 kHz	11 mA + 2 mA		
(1 to 5) kHz	0.33 A + 2 mA		
AC Current - Source <sup>1</sup>	(11 to 20.5) A		Fluke 5522A/SC600 Multi Product Calibrator
	(45 to 100) Hz	25 mA + 5 mA	
	100 Hz to 1 kHz	31 mA + 5 mA	
	(1 to 5) kHz	0.62 A + 5 mA	
Electrical Calibration of Thermocouple Indicators <sup>1</sup>	Type K		Fluke 5522A/SC600 Multi Product Calibrator
	-200 to -100) °C	0.33 °C	
	(-100 to -25) °C	0.18 °C	
	(-25 to 120) °C	0.16 °C	
	(120 to 1 000) °C	0.26 °C	
(1 000 to 1 372) °C	0.4 °C		



Electrical – DC/Low Frequency

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
Electrical Calibration of Thermocouple Indicators <sup>1</sup>	Type J		Fluke 5522A/SC600 Multi Product Calibrator
	(-210 to -100) °C	0.27 °C	
	(-100 to -30) °C	0.16 °C	
	(-30 to 150) °C	0.14 °C	
	(150 to 760) °C	0.17 °C	
	(760 to 1 200) °C	0.23 °C	
	Type T		
	(-250 to -150) °C	0.63 °C	
	(-150 to 0) °C	0.24 °C	
	(0 to 120) °C	0.16 °C	
	(120 to 400) °C	0.14 °C	
	Type E		
	(-250 to -100) °C	0.5 °C	
	(-100 to -25) °C	0.16 °C	
	(-25 to 350) °C	0.14 °C	
	(350 to 650) °C	0.16 °C	
	(650 to 1 000) °C	0.21 °C	
	Type R		
	(0 to 250) °C	0.57 °C	
	(250 to 400) °C	0.35 °C	
	(400 to 1 000) °C	0.33 °C	
(1 000 to 1 767) °C	0.4 °C		
Type S			
(0 to 250) °C	0.47 °C		
(250 to 1 000) °C	0.36 °C		
(1 000 to 1 400) °C	0.37 °C		
(1 400 to 1 767) °C	0.46 °C		
Type N			
(-200 to -100) °C	0.4 °C		
(-100 to -25) °C	0.22 °C		
(-25 to 120) °C	0.19 °C		
(120 to 410) °C	0.18 °C		
(410 to 1 300) °C	0.27 °C		
Electrical Simulation of RTD Indicating Devices <sup>1</sup>	Pt 385, 100 Ω		Fluke 5522A/SC600 Multi Product Calibrator
	(-200 to -80) °C	0.05 °C	
	(-80 to 0) °C	0.05 °C	
	(0 to 100) °C	0.07 °C	
	(100 to 300) °C	0.08 °C	
	(300 to 400) °C	0.09 °C	
	(400 to 630) °C	0.1 °C	
	(630 to 800) °C	0.21 °C	





# ANSI National Accreditation Board

## Electrical – DC/Low Frequency

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
Electrical Simulation of RTD Indicating Devices <sup>1</sup>	Pt 3926, 100 Ω		Fluke 5522A/SC600 Multi Product Calibrator
	(-200 to -80) °C	0.05 °C	
	(-80 to 0) °C	0.05 °C	
	(0 to 100) °C	0.07 °C	
	(100 to 300) °C	0.09 °C	
	(300 to 400) °C	0.1 °C	
	(400 to 630) °C	0.12 °C	
	Pt 3916, 100 Ω		
	(-200 to -190) °C	0.25 °C	
	(-190 to -80) °C	0.04 °C	
	(-80 to 0) °C	0.05 °C	
	(0 to 100) °C	0.06 °C	
	(100 to 260) °C	0.07 °C	
	(260 to 300) °C	0.08 °C	
	(300 to 400) °C	0.09 °C	
	(400 to 600) °C	0.1 °C	
	(600 to 630) °C	0.23 °C	
	Pt 385, 200 Ω		
	(-200 to -80) °C	0.04 °C	
	(-80 to 0) °C	0.04 °C	
	(0 to 100) °C	0.04 °C	
	(100 to 260) °C	0.05 °C	
	(260 to 300) °C	0.12 °C	
	(300 to 400) °C	0.13 °C	
(400 to 600) °C	0.14 °C		
(600 to 630) °C	0.16 °C		
Pt 385, 500 Ω			
(-200 to -80) °C	0.04 °C		
(-80 to 0) °C	0.05 °C		
(0 to 100) °C	0.05 °C		
(100 to 260) °C	0.06 °C		
(260 to 300) °C	0.08 °C		
(300 to 400) °C	0.08 °C		
(400 to 600) °C	0.09 °C		
(600 to 630) °C	0.11 °C		



Electrical – DC/Low Frequency

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
Electrical Simulation of RTD Indicating Devices <sup>1</sup>	Pt 385, 1000 Ω (-200 to -80) °C (-80 to 0) °C (0 to 100) °C (100 to 260) °C (260 to 300) °C (300 to 400) °C (400 to 600) °C (600 to 630) °C PtNi 385, 120 Ω (Ni120) (-80 to 0) °C (0 to 100) °C (100 to 260) °C Cu 427, 10 Ω (-100 to 260) °C	0.03 °C 0.03 °C 0.04 °C 0.05 °C 0.06 °C 0.07 °C 0.07 °C 0.23 °C 0.08 °C 0.08 °C 0.14 °C 0.3 °C	Fluke 5522A/SC600 Multi Product Calibrator
Capacitance Source	(220 to 399.9) pF (0.4 to 1.099) nF (1.1 to 3.299) nF (3.3 to 10.999) nF (11 to 32.999) nF (33 to 109.99) nF	2 pF + 10 pF 5.5 pF + 0.01 nF 17 pF + 0.01 nF 28 pF + 0.01 nF 83 pF + 0.1 nF 0.28 nF + 0.1 nF	Fluke 5522A/SC600 Multi Product Calibrator
Capacitance Source	(110 to 329.99) nF (0.33 to 1.099) μF (1.1 to 3.299) μF (3.3 to 10.999) μF (11 to 32.999) μF (33 to 109.99) μF (110 to 329.99) μF (0.33 to 1.099) mF (1.1 to 3.299) mF (3.3 to 10.999) mF (11 to 32.999) mF (33 to 110) mF	0.83 nF + 0.3 nF 2.8 nF + 1 nF 8.3 nF + 3 nF 28 nF + 10 nF 0.13 μF + 30 nF 0.5 μF + 0.1 μF 1.5 μF + 0.3 μF 5 μF + 1 μF 15 μF + 3 μF 50 μF + 10 μF 0.25 mF + 30 μF 1.1 mF + 0.1 mF	Fluke 5522A/SC600 Multi Product Calibrator
Oscilloscope <sup>1</sup> DC Function Into 50 Ω Into 1 MΩ	(0 to 6.6) V (0 to 130) V	± 0.25 % of output + 40 μV ± 0.05 % of output + 40 μV	Fluke 5522A/SC600 Multi Product Calibrator



Electrical – DC/Low Frequency

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
Oscilloscope <sup>1</sup> Square Wave Into 50 Ω Into 1 MΩ	± 1 mV to ± 6.6 V p-p ± 1mV to ± 130 V p-p	± 0.25 % of output + 40 μV ± 0.1 % of output + 40 μV	Fluke 5522A/SC600 Multi Product Calibrator
Edge Into 50 Ω	(2.5 to 5) V	± 2% of output + 200 μV	
Leveled Sine Wave	50 kHz 50 kHz to 100 MHz (100 to 300) MHz (300 to 600) MHz	± 2% of output + 300 μV ± 3.5% of output + 300 μV ± 4% of output + 300 μV ± 6% of output + 300 μV	
Time marker	50 ms to 5 s 20 ms to 100 ns (20 to 50) ns 10 ns (2 to 5) ns	± 2.5 ns ± 2.5 ps ± 0.5 ps ± 0.25 ps ±0.05 ps	

Length – Dimensional Metrology

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
Gage Blocks <sup>3</sup>	Up to 4 in	(3.4 + 0.81L) μin	Master Gage Blocks
Plain Ring Gages <sup>3</sup>	(0.04 to 12) in	(13 + 4L) μin	LabMaster Laser Measuring System
Plug Gages <sup>3</sup>	Up to 14 in	(7.1 + 4.6L) μin	LabMaster Laser Measuring System
Reference Spheres	Up to 2 in	13 μin	LabMaster Laser Measuring System
Pin Gages	Up to 1 in	9 μin	LabMaster Laser Measuring System
Indicators	Up to 1 in	88 μin	Gage Blocks, Indicator Calibrator
Indicators <sup>1</sup>	Up to 1 in (1 to 5) in	59 μin 64 μin	Gage Blocks

**Length – Dimensional Metrology**

<b>Parameter / Equipment</b>	<b>Range</b>	<b>Expanded Uncertainty of Measurement (+/-)</b>	<b>Reference Standard, Method and/or Equipment</b>
Micrometers and Depth Micrometers <sup>3</sup>	Up to 50 in	$(90 + 7.3L) \mu\text{in}$	Gage Blocks
Calipers <sup>1,3</sup>	Up to 80 in	$(573 + 1.6L) \mu\text{in}$	Gage Blocks
Height Gages <sup>1,3</sup>	Up to 40 in	$(27 + 4.3L) \mu\text{in}$	Gage Blocks
Shims	Up to 250 mils	5.9 $\mu\text{in}$	LabMaster Laser Measuring System
Thickness coating gage <sup>1</sup>	Up to 250 mils	120 $\mu\text{in}$	Shims
Optical Comparators <sup>1</sup> Linearity Angularity Magnification	Up to 16 in (0 to 180) Deg (10 to 100) X	0.001 4 in 5 arcsec 0.002 1 in	Inspection Master Angle Block
Microscopes <sup>1</sup>	Up to 1.0 in	1 200 $\mu\text{in}$	Stage Micrometer I1110, Ruler
Precision Rules	(6 to 72) in	0.012 in	Precision Rule and microscope
Measuring Tapes	(6 to 100) ft	0.073 in	Precision Rule Microscope
Roughness gage	16.1 $\mu\text{in Ra}$ 119.5 $\mu\text{in Ra}$	1.6 $\mu\text{in}$ 3 $\mu\text{in}$	Roughness standard
Surface Plate Overall Flatness <sup>1,3</sup>	Up to (72 x 144) in	$4.7\sqrt{(D/4)}$ in	In accordance with ASME B89.3.7 using Electronic Leveling System
60 Degree Thread Plugs - Pitch Diameter	Up to 8 in	$(69 + 0.8L) \mu\text{in}$	Labmaster Laser Measuring System
Thread Wires	Up to 0.15 in	11 $\mu\text{in}$	LabMaster Laser Measuring System
Angle	Up to 90 deg	1.9 arcmin	Optical Comparator
Protractors	Up to 360 deg	0.37 arcmin	Angle Blocks, Height Gage
Protractors <sup>1</sup>	Up to 360 deg	35 arcmin	Angle Blocks
Electronic Levels	Up to 400 s	4.3 s	Sine Plate, Gage Blocks SSCLD-12-01



**Length – Dimensional Metrology**

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
Length	0 to 100 in	$(113 + 6.5L) \mu\text{in}$	Gage blocks

**Mass and Mass Related**

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
Vacuum <sup>1</sup>	Up to 27 in Hg	0.006 inHg	Transducer
Balances <sup>2,5</sup> (0.0001 g resolution) (0.001 g resolution) (0.01 g resolution) (0.1 g resolution) (1 g resolution)	(0 to 200) g (0 to 1000) g (0 to 10) kg	0.1 mg 0.6 mg 5.8 mg 58 mg 0.58 g	Class F1 Weights to NIST Handbook 44
Scales <sup>2,5</sup> (0.001 lb resolution) (0.01 lb resolution) (0.1 lb resolution) (1 lb resolution) (10 lb resolution)	(0 to 100) lb (0 to 500) lb (0 to 5000) lb (0 to 10 000) lb (0 to 400 000) lb	0.001 lb 0.006 lb 0.058 lb 0.58 lb 5.8 lb	Class F1 and F Weights to NIST Handbook 44
Scales <sup>2</sup>	(1 000 to 2 000) lb (2 000 to 5 000) lb (5 000 to 10 000) (10 000 to 20 000) lb (20 000 to 50 000) lb (50 000 to 100 000) lb (100 000 to 200 000) lb (200 000 to 300 000) lb (300 000 to 400 000) lb	0.58 lb 1.2 lb 2.3 lb 5.8 lb 12 lb 23 lb 23 lb 58 lb 58 lb	Class F1 and F Weights to NIST Handbook 44
Torque Transducers <sup>1</sup>	(0.005 2 to 250) lbf-in (1 to 1 000) lbf-ft	0.061 % of reading 0.12 % of reading	Weights, Torque Arm
Torque Wrenches <sup>1</sup>	(0.0052 to 50) lbf-in (>50 to 100) lbf-in (1 to 250) lbf-ft (>250 to 1 000) lbf-ft	0.52 % of reading 0.60 % of reading 0.61 % of reading 0.59 % of reading	Torque Transducer

**Mass and Mass Related**

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
Force <sup>1</sup> - Compression & Tension	(0 to 100) lbf (>100 to 500) lbf (>500 to 1 000) lbf (>1 000 to 10 000) lbf (>10 000 to 100 000) lbf	0.006 lbf 0.03 lbf 0.07 lbf 0.24 lbf 2.34 lbf	Ultra-Precision Load Cells, Load Cells, Weights
Pressure Gages  Air	Up to 50 in H <sub>2</sub> O Up to 10 psi Up to 100 psi Up to 300 psi Up to 1 000 psi Up to 5 000 psi	0.001 3 in H <sub>2</sub> O 0.001 3 psi 0.006 1 psi 0.016 psi 0.14 psi 1.1 psi	Transducer
	(5.8 to 1 000) psi	(0.003 + 0.6R) psi	Deadweight Tester
Pressure Gages <sup>1</sup> Oil	Up to 10 000 psi	3.1 psi	Deadweight Tester
Pressure Gages <sup>1</sup>  Air	Up to 300 psi Up to 50 in H <sub>2</sub> O Up to 100 psi Up to 1 000 psi	0.06 psi 0.02 in H <sub>2</sub> O 0.09 psi 0.16 psi	Transducer
Mass ASTM Classes 5, 6, & 7 and NIST Class F	1 g 2 g 3 g 5 g 10 g 20 g 50 g 100 g 200 g 300 g 500 g 1 000 g 2 000 g 3 000 g 5 000 g	0.06 mg 0.05 mg 0.05 mg 0.05 mg 0.05 mg 0.05 mg 0.05 mg 0.06 mg 0.11 mg 1.3 mg 1.3 mg 1.3 mg 2.3 mg 2.3 mg 2.8 mg	Balance, ASTM Class 1 weights
Indirect Verification to ASTM E10 of Brinell Hardness Testers <sup>1</sup>	(72 to 277) HBW	3.4 HBW	Hardness Blocks

**Mass and Mass Related**

<b>Parameter / Equipment</b>	<b>Range</b>	<b>Expanded Uncertainty of Measurement (+/-)</b>	<b>Reference Standard, Method and/or Equipment</b>
Rockwell Hardness Testers <sup>1</sup>	HRA		Indirect Verification to ASTM E18 using Hardness Blocks
	Low	0.37 HRA	
	Middle	0.37 HRA	
	High	0.27 HRA	
	HRBW		
	Low	0.53 HRBW	
	Middle	0.32 HRBW	
	High	0.32 HRBW	
	HRC		
	Low	0.38 HRC	
	Middle	0.38 HRC	
	High	0.29 HRC	
	HREW		
	Low	0.53 HRE	
	Middle	0.53 HRE	
High	0.53 HRE		
Rockwell Superficial Hardness Testers <sup>1</sup>	HR15N		Indirect Verification to ASTM E18 using Hardness Blocks
	Low	0.57 HR15N	
	Middle	0.57 HR15N	
	High	0.27 HR15N	
	HR30N		
	Low	0.41 HR30N	
	Middle	0.41 HR30N	
	High	0.41 HR30N	
	HR45N		
	Low	0.51 HR45N	
	Middle	0.51 HR45N	
	High	0.51 HR45N	
	HR15TW		
	Low	0.49 HR15TW	
	Middle	0.41 HR15TW	
	High	0.41 HR15TW	
	HR30TW		
	Low	0.43 HR30TW	
Middle	0.37 HR30TW		
High	0.37 HR30TW		

**Mass and Mass Related**

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
Durometers Indenter Dimensions Extension Diameter/Length Indenter Radius Indenter Angle  Spring Force Types A, B, E, O Types D, C, DO	(0 to 0.1) in (0 to 0.15) in (0 to 0.05) in (25 to 40) °  Up to 8.05 N Up to 44.45 N	0.000 28 in 0.000 28 in 0.000 28 in 0.001 4°  0.098 N 0.58 N	Direct Verification to ASTM D2240  Optical Projection  Weights
Gas Flow	492 fpm 984 fpm 1969 fpm 2953 fpm	25 fpm 25 fpm 28 fpm 31 fpm	Anemometer & Open Jet Wind Tunnel

**Thermodynamic**

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
Temperature - Infrared <sup>2</sup>	Up to 500 °C	(0.17 + .001 3R) °C	Black Body (flat Plate) $\epsilon = 0.95, \lambda = (8 \text{ to } 14) \mu\text{m}$
	Up to 1 200 °C	(2.1 + 0.001 5R) °C	Black Body (cavity) $\epsilon = 0.99, \lambda = (8 \text{ to } 14) \mu\text{m}$
Chart Recorders Relative Humidity Temperature	(20 to 90) %RH (-17 to 177) °C	1.5 %RH 0.57 °C	Environmental Chamber, Datalogger
Temperature <sup>1</sup>	(-200 to -100) °C (-100 to -25) °C (-25 to 120) °C (120 to 1 000) °C (1 000 to 1 372) °C	0.26 °C	Thermo calibrator, Data logger, Temperature probe
Temperature probes	(-15 to 1 200) °C	(0.53 + 0.003 6R) °C	Dry well, PRT thermocouple, Type S thermocouple, Environmental Chamber




**Time and Frequency**

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
Stop Watches	0.001 s to 24 h	38 ms	Stopwatch Calibrator
Optical Tachometers (1 to 10 000) rpm	0.5 Hz to 16.6 kHz	0.25 parts in 10 <sup>6</sup> Hz	Fluke 5522A/SC600 Multi Product Calibrator
Frequency - Source <sup>1</sup>	(0.01 to 119.99) Hz (120 to 1199.9) Hz (1.2 to 11.999) kHz (12 to 119.99) kHz (120 to 1199.9) kHz (1.2 to 2) MHz	0.000 3 Hz 0.003 Hz 0.03 Hz 0.3 Hz 3 Hz 5 Hz	Fluke 5522A/SC600 Multi Product Calibrator
Frequency - Measure <sup>1</sup>	(1 to 40) Hz 25 ms to 1 s 40 Hz to 10 MHz 25 ms to 100 ns	0.05 % of reading 0.05 % of reading 0.01 % of reading 0.01 % of reading	HP 3458A Opt 002 Multimeter

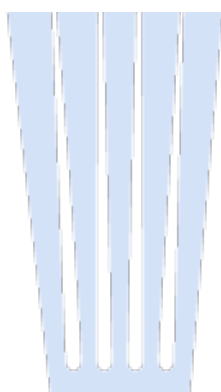
Calibration and Measurement Capability (CMC) is expressed in terms of the measurement parameter, measurement range, expanded uncertainty of measurement and reference standard, method, and/or equipment. The expanded uncertainty of measurement is expressed as the standard uncertainty of the measurement multiplied by a coverage factor of 2 ( $k=2$ ), corresponding to a confidence level of approximately 95%.

Notes:

1. On-site calibration service is available for this parameter, since on-site conditions are typically more variable than those in the laboratory, larger measurement uncertainties are expected on-site than what is reported on the accredited scope
2. Scale calibrations performed on-site only.
3. The use of (L) signifies an expression of applied Length in inches, the use of (D) signifies an expression of applied Diagonal Length in inches.
4. This scope is formatted as part of a single document including Certificate of Accreditation No. AC-1756.



\_\_\_\_\_  
Vice President





# CERTIFICATE OF ACCREDITATION

**ANSI National Accreditation Board**  
11617 Coldwater Road, Fort Wayne, IN 46845 USA

This is to certify that

**System Scale Corporation**  
**4808 Alma Highway**  
**Van Buren, AR 72956**

has been assessed by ANAB and meets the requirements of international standard

**ISO/IEC 17025:2017**

and national standards

**ANSI/NCSL Z540-1-1994 (R2002)**

while demonstrating technical competence in the field of

**CALIBRATION**

Refer to the accompanying Scope of Accreditation for information regarding the types of activities to which this accreditation applies

AC-1756.01  
Certificate Number

  
ANAB Approval

Certificate Valid Through: 02/01/2021  
Version No. 003 Issued: 02/05/2020



This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).



SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017 AND ANSI/NCSL Z540-1-1994 (R2002)

System Scale Corporation

4808 Alma Highway
Van Buren, AR 72956
Sean Rainey 501-562-2900
srainey@system-scale.com

CALIBRATION

Valid to: February 1, 2021

Certificate Number: AC-1756.01

Mass and Mass Related

Table with 4 columns: Parameter/Equipment, Range, Calibration and Measurement Capability [Expressed as Uncertainty (±)], Reference Standard or Equipment. Rows include Balances and Scales with various resolutions and ranges.

Calibration and Measurement Capability (CMC) is expressed in terms of the measurement parameter, measurement range, expanded uncertainty of measurement and reference standard, method, and/or equipment. The expanded uncertainty of measurement is expressed as the standard uncertainty of the measurement multiplied by a coverage factor of 2 (k=2), corresponding to a confidence level of approximately 95%.

Notes:

- 1. Only On-site calibration service is available for this parameter, since on-site conditions are typically more variable than those in the laboratory, larger measurement uncertainties are expected on-site than what is reported on the accredited scope
2. Uncertainties for Scales and Balances will be larger if the least significant digit increments by 2 or 5.
3. This scope is formatted as part of a single document including Certificate of Accreditation No. AC-1756.01.

Signature of R. D. [unclear]
Vice President





# CERTIFICATE OF ACCREDITATION

**ANSI National Accreditation Board**  
11617 Coldwater Road, Fort Wayne, IN 46845 USA

This is to certify that

**System Scale Corporation**  
**2212 N. Yellowood Avenue**  
**Broken Arrow, OK 74012**

has been assessed by ANAB and meets the requirements of international standard

**ISO/IEC 17025:2017**

and national standards

**ANSI/NCSL Z540-1-1994 (R2002)**

while demonstrating technical competence in the field of

**CALIBRATION**

Refer to the accompanying Scope of Accreditation for information regarding the types of activities to which this accreditation applies

AC-1756.02

Certificate Number



ANAB Approval

Certificate Valid Through: 02/01/2021  
Version No. 003 Issued: 02/05/2020



This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).



SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017 AND ANSI/NCSL Z540-1-1994 (R2002)

System Scale Corporation

2212 N. Yellowwood Avenue
Broken Arrow, OK 74012
Sean Rainey 501-562-2900
srainey@system-scale.com

CALIBRATION

Valid to: February 1, 2021

Certificate Number: AC-1756.02

Mass and Mass Related

Table with 4 columns: Parameter/Equipment, Range, Calibration and Measurement Capability [Expressed as Uncertainty (±)], Reference Standard or Equipment. Rows include Balances and Scales with various resolutions and ranges.

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Notes:

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2. Uncertainties for Scales and Balances will be larger if the least significant digit increments by 2 or 5.
3. This scope is formatted as part of a single document including Certificate of Accreditation No. AC-1756.02.

Signature of R.D. [unclear]
Vice President





# CERTIFICATE OF ACCREDITATION

**ANSI National Accreditation Board**  
11617 Coldwater Road, Fort Wayne, IN 46845 USA

This is to certify that

**System Scale Corporation**  
**6579 Reese Road**  
**Memphis, TN 38133**

has been assessed by ANAB and meets the requirements of international standard

**ISO/IEC 17025:2017**

and national standards

**ANSI/NCSL Z540-1-1994 (R2002)**

while demonstrating technical competence in the field of

**CALIBRATION**

Refer to the accompanying Scope of Accreditation for information regarding the types of activities to which this accreditation applies

AC-1756.04

Certificate Number

  
ANAB Approval

Certificate Valid Through: 02/01/2021  
Version No. 003 Issued: 02/05/2020



This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).



SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017 AND ANSI/NCSL Z540-1-1994 (R2002)

System Scale Corporation

6579 Reese Road
Memphis, TN 38133
Sean Rainey 501-562-2900
srainey@system-scale.com

CALIBRATION

Valid to: February 1, 2021

Certificate Number: AC-1756.04

Mass and Mass Related

Table with 4 columns: Parameter/Equipment, Range, Calibration and Measurement Capability [Expressed as Uncertainty (±)], Reference Standard or Equipment. Rows include Balances and Scales with various resolutions and ranges.

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Notes:

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2. Uncertainties for Scales and Balances will be larger if the least significant digit increments by 2 or 5.
3. This scope is formatted as part of a single document including Certificate of Accreditation No. AC-1756.04.

Signature of R.D. [unclear]
Vice President





# CERTIFICATE OF ACCREDITATION

**ANSI National Accreditation Board**  
11617 Coldwater Road, Fort Wayne, IN 46845 USA

This is to certify that

**System Scale Corporation**  
**1420 Donelson Pike, Suite B7**  
**Nashville, TN 37217**

has been assessed by ANAB and meets the requirements of international standard

**ISO/IEC 17025:2017**

and national standards

**ANSI/NCSL Z540-1-1994 (R2002)**

while demonstrating technical competence in the field of

**CALIBRATION**

Refer to the accompanying Scope of Accreditation for information regarding the types of activities to which this accreditation applies

AC-1756.05

Certificate Number

  
ANAB Approval

Certificate Valid Through: 02/01/2021  
Version No. 003 Issued: 02/05/2020



This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).





SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017 AND ANSI/NCSL Z540-1-1994 (R2002)

System Scale Corporation

1420 Donelson Pike, Suite B7
Nashville, TN 37217
Sean Rainey 501-562-2900
srainey@system-scale.com

CALIBRATION

Valid to: February 1, 2021

Certificate Number: AC-1756.05

Mass and Mass Related

Table with 4 columns: Parameter/Equipment, Range, Calibration and Measurement Capability [Expressed as Uncertainty (±)], Reference Standard or Equipment. Rows include Balances and Scales with various resolutions and ranges.

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Notes:

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2. Uncertainties for Scales and Balances will be larger if the least significant digit increments by 2 or 5.
3. This scope is formatted as part of a single document including Certificate of Accreditation No. AC-1756.05.

Signature of R. D. [unclear]
Vice President





# CERTIFICATE OF ACCREDITATION

**ANSI National Accreditation Board**  
11617 Coldwater Road, Fort Wayne, IN 46845 USA

This is to certify that

**System Scale Corporation**  
**595 Pearl Park Plaza**  
**Jackson, MS 39208**

has been assessed by ANAB and meets the requirements of international standard

**ISO/IEC 17025:2017**

and national standards

**ANSI/NCSL Z540-1-1994 (R2002)**

while demonstrating technical competence in the field of

**CALIBRATION**

Refer to the accompanying Scope of Accreditation for information regarding the types of activities to which this accreditation applies

AC-1756.06

Certificate Number



ANAB Approval

Certificate Valid Through: 02/01/2021  
Version No. 003 Issued: 02/05/2020



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SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017 AND ANSI/NCSL Z540-1-1994 (R2002)

System Scale Corporation

595 Pearl Park Plaza
Jackson, MS 39208
Sean Rainey 501-562-2900
srainey@system-scale.com

CALIBRATION

Valid to: February 1, 2021

Certificate Number: AC-1756.06

Mass and Mass Related

Table with 4 columns: Parameter/Equipment, Range, Calibration and Measurement Capability [Expressed as Uncertainty (±)], Reference Standard or Equipment. Rows include Balances and Scales with various resolutions and ranges.

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Notes:

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2. Uncertainties for Scales and Balances will be larger if the least significant digit increments by 2 or 5.
3. This scope is formatted as part of a single document including Certificate of Accreditation No. AC-1756.06.

Signature of R. D. [unclear]
Vice President





# CERTIFICATE OF ACCREDITATION

**ANSI National Accreditation Board**  
11617 Coldwater Road, Fort Wayne, IN 46845 USA

This is to certify that

**System Scale Corporation**  
**6215-120 Rangeline Road**  
**Theodore, AL 36582**

has been assessed by ANAB and meets the requirements of international standard

**ISO/IEC 17025:2017**

and national standards

**ANSI/NCSL Z540-1-1994 (R2002)**

while demonstrating technical competence in the field of

**CALIBRATION**

Refer to the accompanying Scope of Accreditation for information regarding the types of activities to which this accreditation applies

AC-1756.07

Certificate Number



ANAB Approval

Certificate Valid Through: 02/01/2021  
Version No. 003 Issued: 02/05/2020



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SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017 AND ANSI/NCSL Z540-1-1994 (R2002)

System Scale Corporation

6215-120 Rangeline Road
Theodore, AL 36582
Sean Rainey 501-562-2900
srainey@system-scale.com

CALIBRATION

Valid to: February 1, 2021

Certificate Number: AC-1756.07

Mass and Mass Related

Table with 4 columns: Parameter/Equipment, Range, Calibration and Measurement Capability [Expressed as Uncertainty (±)], Reference Standard or Equipment. Rows include Balances and Scales with various resolutions and ranges.

Calibration and Measurement Capability (CMC) is expressed in terms of the measurement parameter, measurement range, expanded uncertainty of measurement and reference standard, method, and/or equipment. The expanded uncertainty of measurement is expressed as the standard uncertainty of the measurement multiplied by a coverage factor of 2 (k=2), corresponding to a confidence level of approximately 95%.

Notes:

- 1. Only On-site calibration service is available for this parameter, since on-site conditions are typically more variable than those in the laboratory, larger measurement uncertainties are expected on-site than what is reported on the accredited scope
2. This scope is formatted as part of a single document including Certificate of Accreditation No. AC-1756.07.

Handwritten signature of R.D.R. over a horizontal line, with the text 'Vice President' below it.



# CERTIFICATE OF ACCREDITATION

**ANSI National Accreditation Board**  
11617 Coldwater Road, Fort Wayne, IN 46845 USA

This is to certify that

**System Scale Corporation**  
**4393 West 96<sup>th</sup> Street**  
**Indianapolis, IN 46268**

has been assessed by ANAB and meets the requirements of international standard

**ISO/IEC 17025:2017**

and national standards

**ANSI/NCSL Z540-1-1994 (R2002)**

while demonstrating technical competence in the field of

**CALIBRATION**

Refer to the accompanying Scope of Accreditation for information regarding the types of activities to which this accreditation applies

AC-1756.08

Certificate Number

  
ANAB Approval

Certificate Valid Through: 02/01/2021  
Version No. 003 Issued: 02/05/2019



This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).



# ANSI National Accreditation Board

## SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017 AND ANSI/NCSL Z540-1-1994 (R2002)

### System Scale Corporation

4393 West 96<sup>th</sup> Street  
Indianapolis, IN 46268  
Sean Rainey 501-562-2900  
srainey@system-scale.com

### CALIBRATION

Valid to: **February 1, 2021**

Certificate Number: **AC-1756.08**

#### Mass and Mass Related

Parameter/ Equipment	Range	Calibration and Measurement Capability [Expressed as Uncertainty ( $\pm$ )]	Reference Standard or Equipment
Balances <sup>1,2</sup> Resolution: 0.0001 g 0.001 g 0.01 g 0.1 g 1 g	(0 to 200) g (0 to 1000) g  (0 to 10) kg	0.1 mg 0.6 mg 5.8 mg 58 mg 0.58 g	Class 1, F1 and F Weights NIST Handbook 44
Scales <sup>1,2</sup> Resolution: 0.001 lb 0.01 lb 0.1 lb 1 lb 10 lb	(0 to 100) lb (0 to 500) lb (0 to 5000) lb (0 to 10 000) lb (0 to 400 000) lb	0.001 lb 0.006 lb 0.058 lb 0.58 lb 5.8 lb	Class F1 and F Weights NIST Handbook 44

Calibration and Measurement Capability (CMC) is expressed in terms of the measurement parameter, measurement range, expanded uncertainty of measurement and reference standard, method, and/or equipment. The expanded uncertainty of measurement is expressed as the standard uncertainty of the measurement multiplied by a coverage factor of 2 ( $k=2$ ), corresponding to a confidence level of approximately 95%.

#### Notes:

1. Only On-site calibration service is available for this parameter, since on-site conditions are typically more variable than those in the laboratory, larger measurement uncertainties are expected on-site than what is reported on the accredited scope.
2. Uncertainties for Scales and Balances will be larger if the least significant digit increments by 2 or 5.
3. This scope is formatted as part of a single document including Certificate of Accreditation No. AC-1756.08.



Vice President



# CERTIFICATE OF ACCREDITATION

**ANSI National Accreditation Board**  
11617 Coldwater Road, Fort Wayne, IN 46845 USA

This is to certify that

**System Scale Corporation**  
**34624 LA-16**  
**Baton Rouge, LA 70706**

has been assessed by ANAB and meets the requirements of international standard

**ISO/IEC 17025:2017**

and national standards

**ANSI/NCSL Z540-1-1994 (R2002)**

while demonstrating technical competence in the field of

**CALIBRATION**

Refer to the accompanying Scope of Accreditation for information regarding the types of activities to which this accreditation applies

AC-1756.09

Certificate Number



ANAB Approval

Certificate Valid Through: 02/01/2021  
Version No. 003 Issued: 02/05/2020



This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).





SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017 AND ANSI/NCSL Z540-1-1994 (R2002)

System Scale Corporation

34624 LA-16
Baton Rouge, LA 70706
Sean Rainey 501-562-2900
srainey@system-scale.com

CALIBRATION

Valid to: February 1, 2021

Certificate Number: AC-1756.09

Mass and Mass Related

Table with 4 columns: Parameter/Equipment, Range, Calibration and Measurement Capability [Expressed as Uncertainty (±)], Reference Standard or Equipment. Rows include Balances and Scales with various resolutions and ranges.

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Notes:

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2. This scope is formatted as part of a single document including Certificate of Accreditation No. AC-1756.09.

Signature of R. D. [unclear]
Vice President